## Notice of References Cited Application/Control No. 10/801,987 Examiner Jack Smith Applicant(s)/Patent Under Reexamination FUKAWA ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
	В	US-		•	,
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	- 1	US-			
	J	US-			
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## **FOREIGN PATENT DOCUMENTS**

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## **NON-PATENT DOCUMENTS**

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U	English copy of abstracts for: JP2000-114416, 04-2000, Sakamoto						
	٧.	English copy of abstracts for: JP2002-346788, 04-2002, Nakahara et al.						
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